A class of rank-based test for left-truncated and right-censored data

Pao-sheng Shen

Abstract A class of rank-based tests is proposed for the two-sample problem with left-truncated and right-censored data. The class contains as special cases the extension of log-rank test and Gehan test. The asymptotic distribution theory of the test is presented. The small-sample performance of the test is investigated under a variety of situations by means of Mone Carlo simulations.